

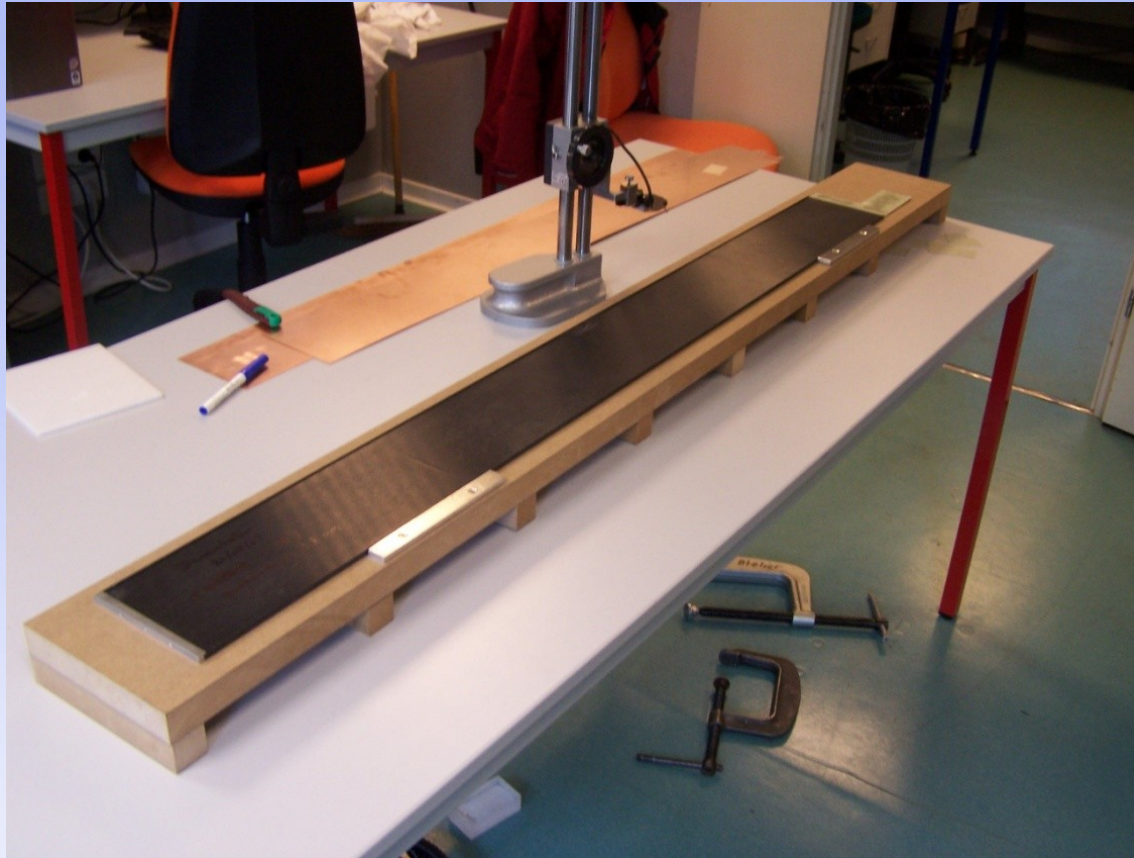
# Progress on FEV7/8 in France

## Mechanical aspects



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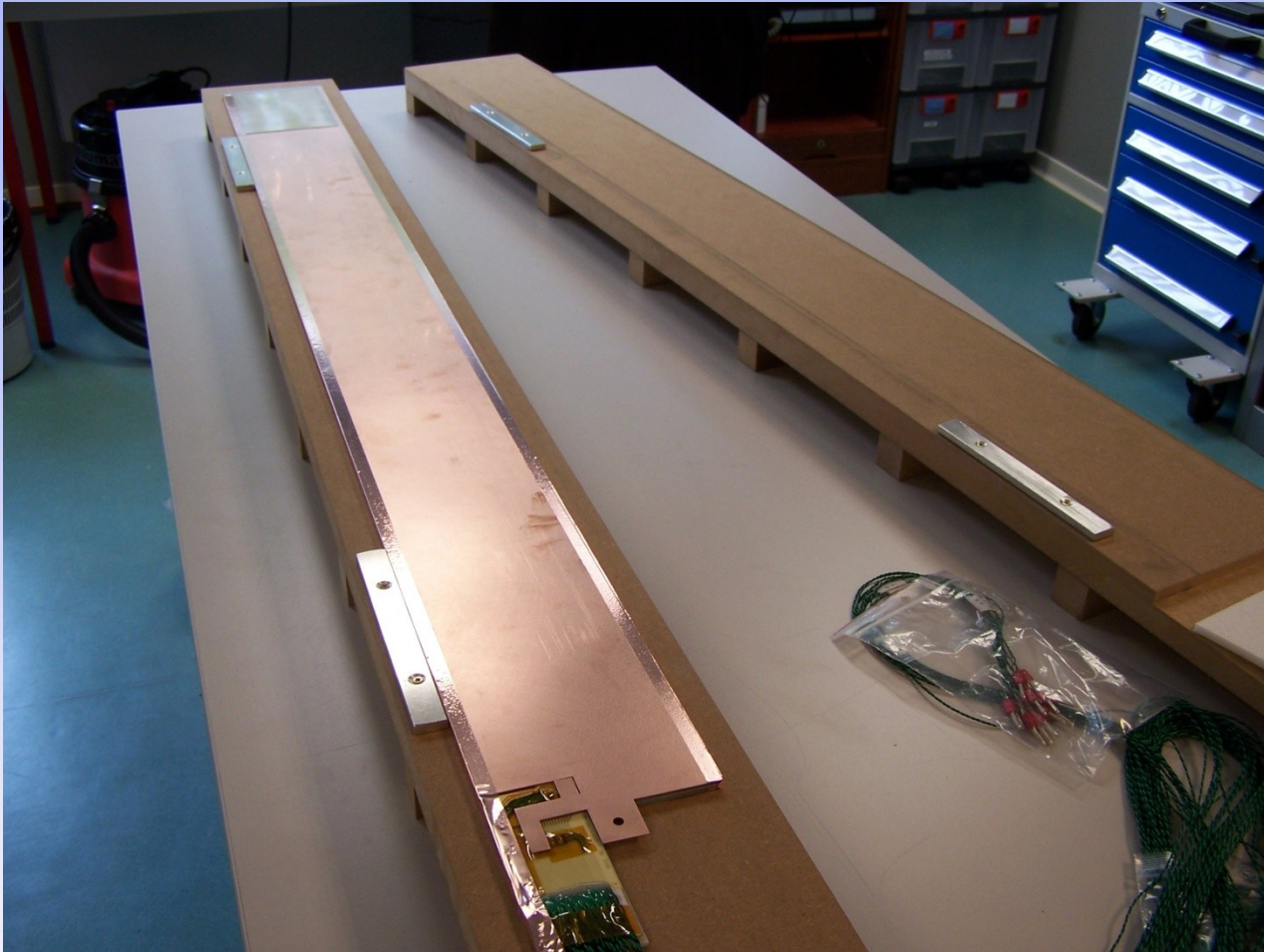
# EUNET mechanics, General overview



Tungsten Slab structure

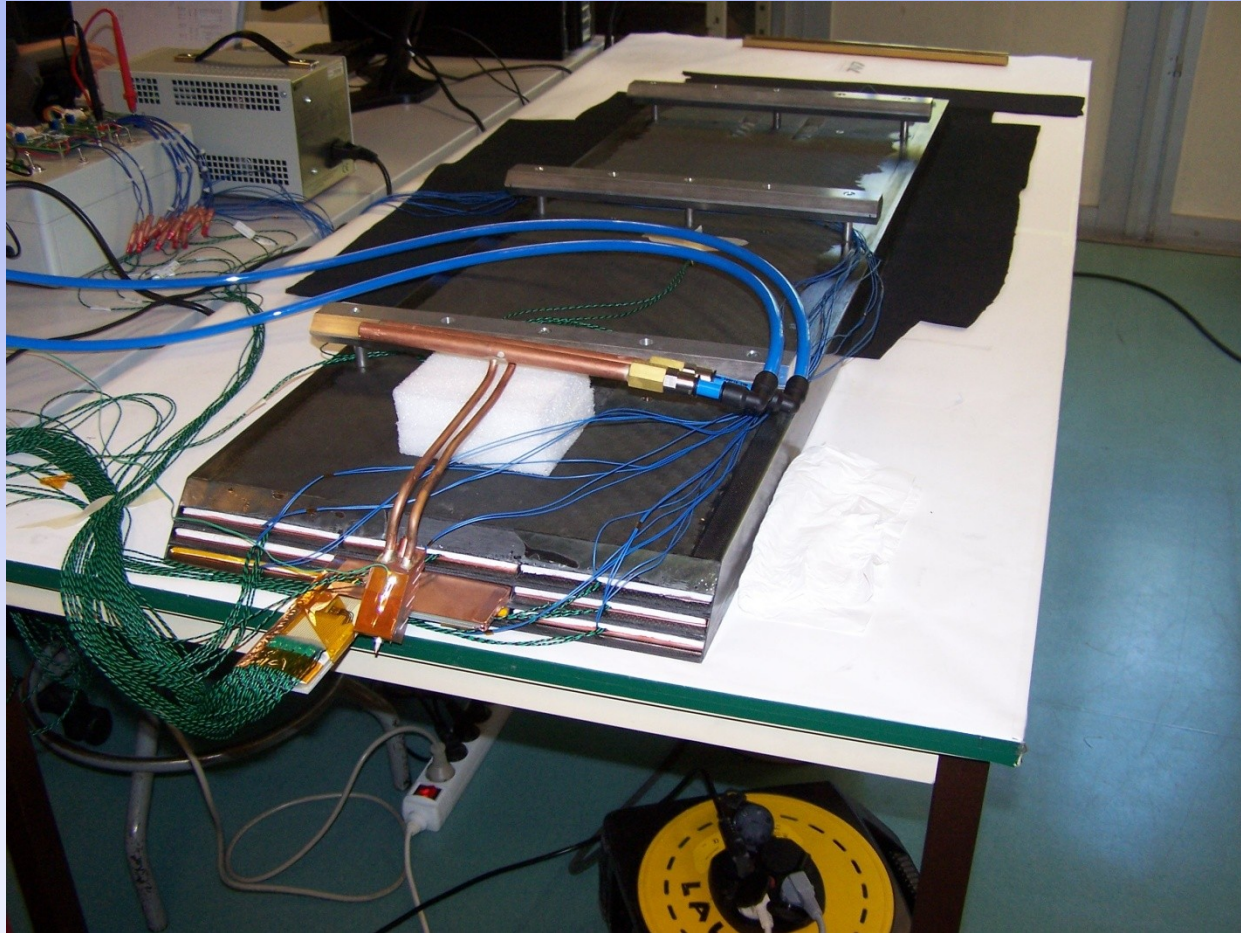


Thermal test ASU (connected between them) inside Slab structure



Finish thermal test Slab





Slab introduce into thermal test module

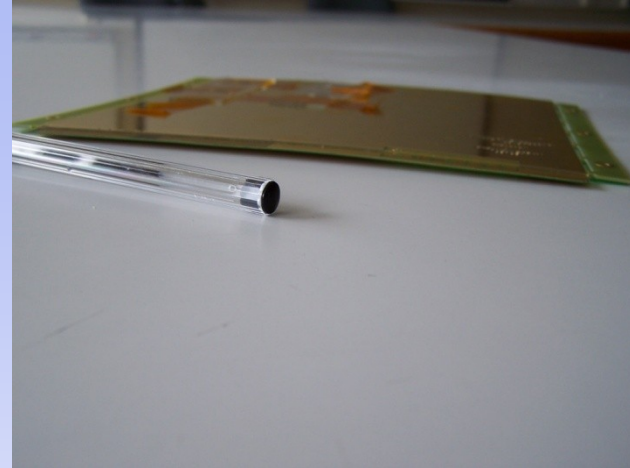
# FEV7 Board, Mechanical current state

## Planarity challenge

- « Horse saddle shape » deformations
- 2mm of deflection (order of magnitude)

### **Causes**

- **Bimetallic effect during elaboration**  
(PCB = copper layers and composite layers)



*Remark :*

- *Elastic modulus or/and thermal expansion are different according to direction in plane.*  
(Horse saddle shape) .

## Which consequences ?

### *Difficulties :*

- Glue flat wafer on curved PCB.
- Connect bend out ASU between them
- Final Slab thickness.

=> PCB must be hold flat during operations

Main issue was stress level in wafer and glue when PCB are release.

**Question is : What PCB deflection was acceptable ?**

## Finite Element Methode modelisation of ASU

Objective : Estimate stress inside glue and wafer when ASU was released.

### Materials proprieties

- **PCB**

Young modulus = 32 GPa

- **Conductive Glue** : EPO-TEK E4110

Young modulus = 3.6 GPa

Failure stress = 8.7 MPa

- **ACP (Anisotropic Conductive Film)**

Failure stress = 10 to 50 MPa

- **Si Wafer**

Young modulus = 185 Gpa

Failure stress = 140 MPa

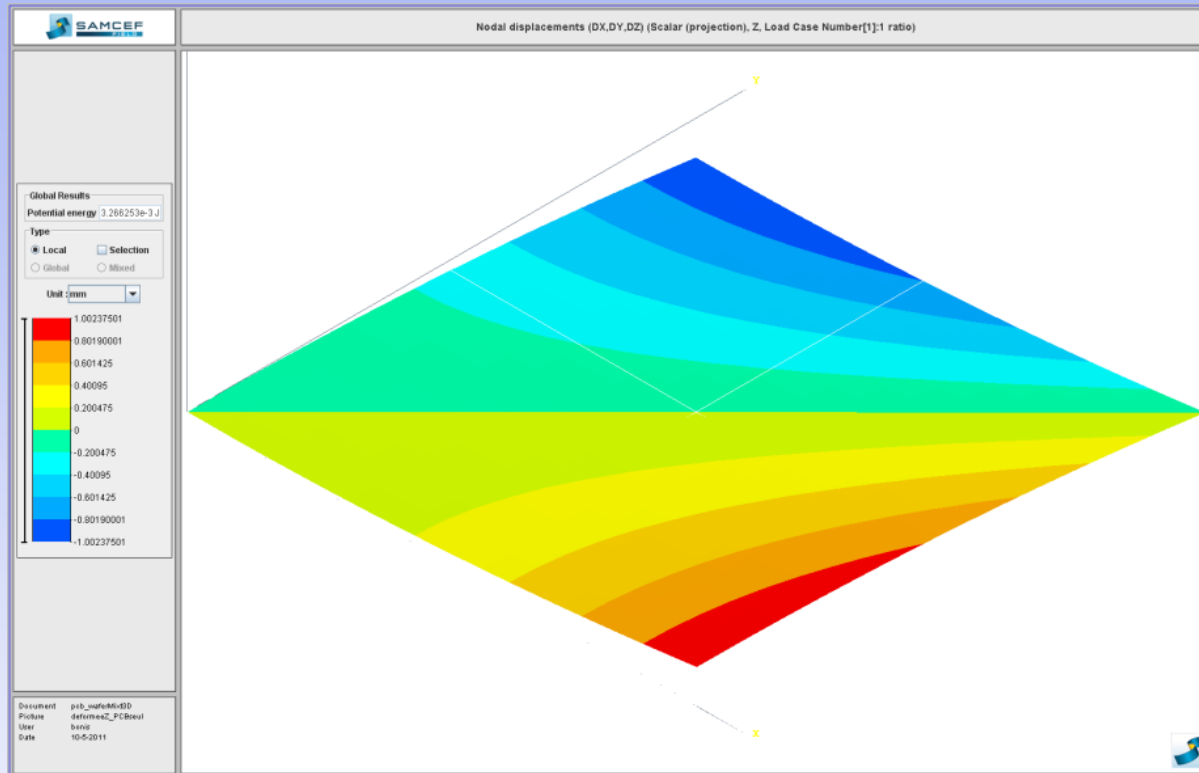


## Modelisation of PCB bending without wafer

- Only one quarter of PCB modeled : exploit symmetry of board.
- PCB separated in two pieces :  $2 \times 0.6\text{mm} = 1.2\text{mm}$  thickness
- (2 shells in model)
- Equivalent PCB material,  $E = 32 \text{ GPa}$ , with unidirectional thermal expansion coefficient.
- The two shells are linked : nodes connected in all directions.
- Opposite variation of temperature was arbitrary imposed on shells: until deflection equal 1mm.
- The total PCB plan expansion is zero (no bimetallic effect with wafer when it will be added).

# Preliminary results :

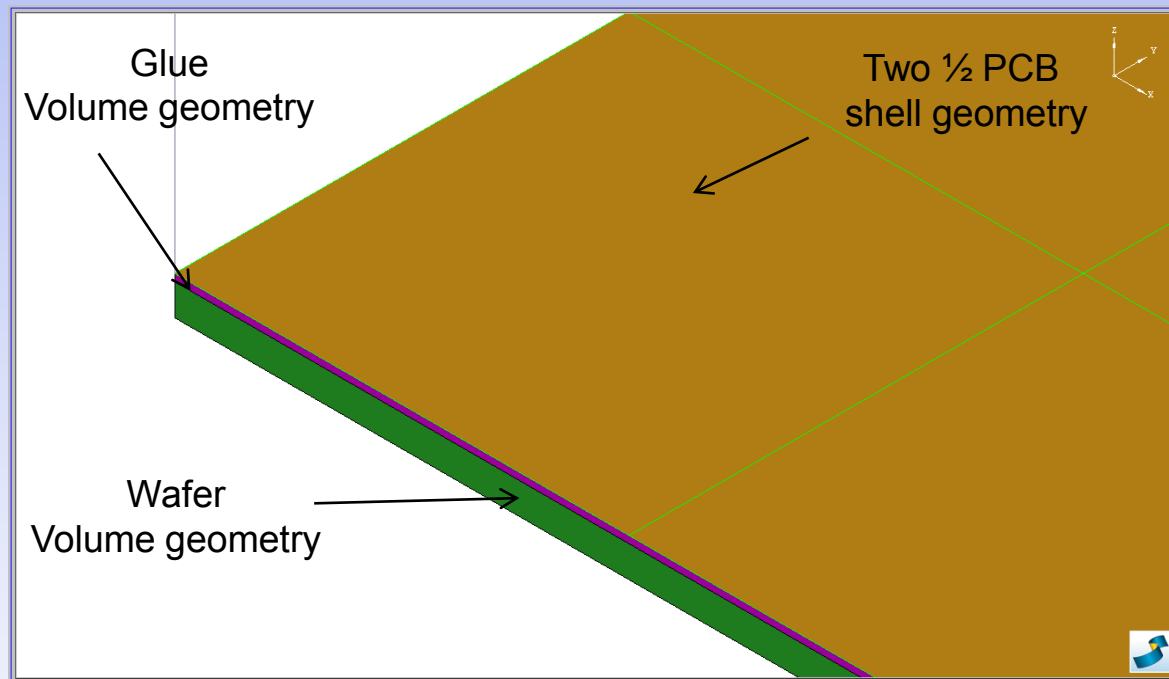
## Simulate deformations and efforts of PCB



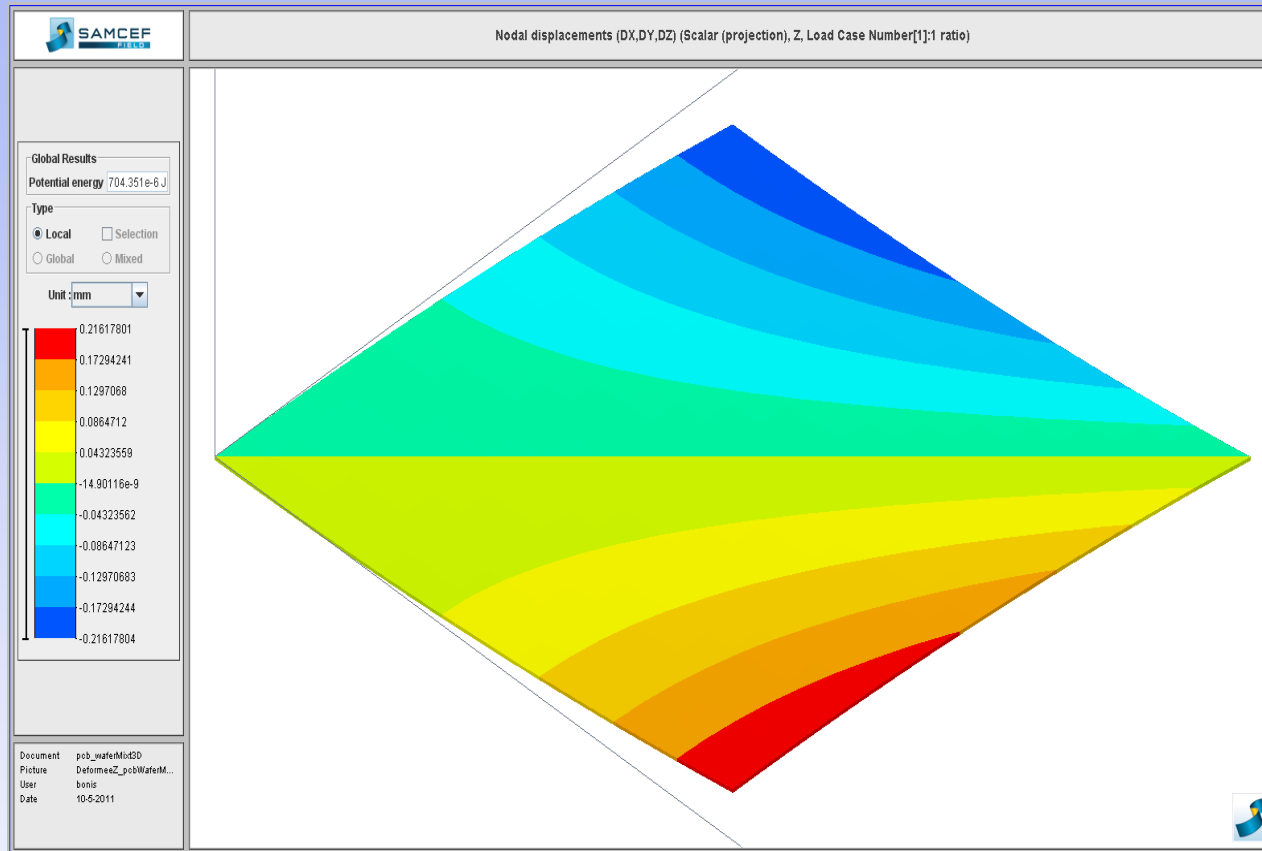
Deformations of  $\frac{1}{4}$  shell PCB (2 symmetries applied).  
Maximale Deflection was 1mm.

## ASU modelisation

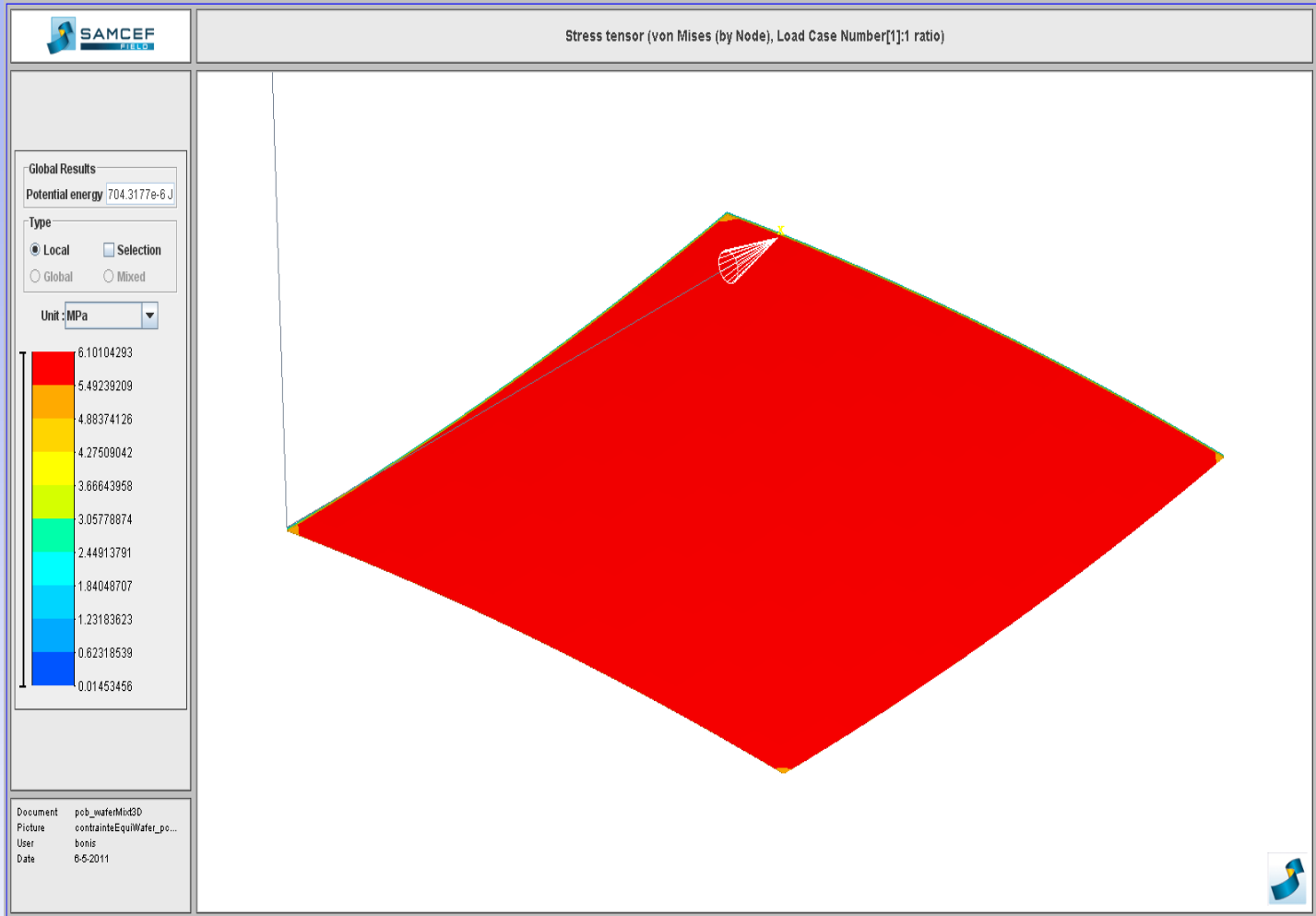
Glue and wafer (two 3D solid volumes) was connected to PCB shell.  
Same variation of temperature than previously was imposed on the 2 half PCB shell.



# ASU simulation Results

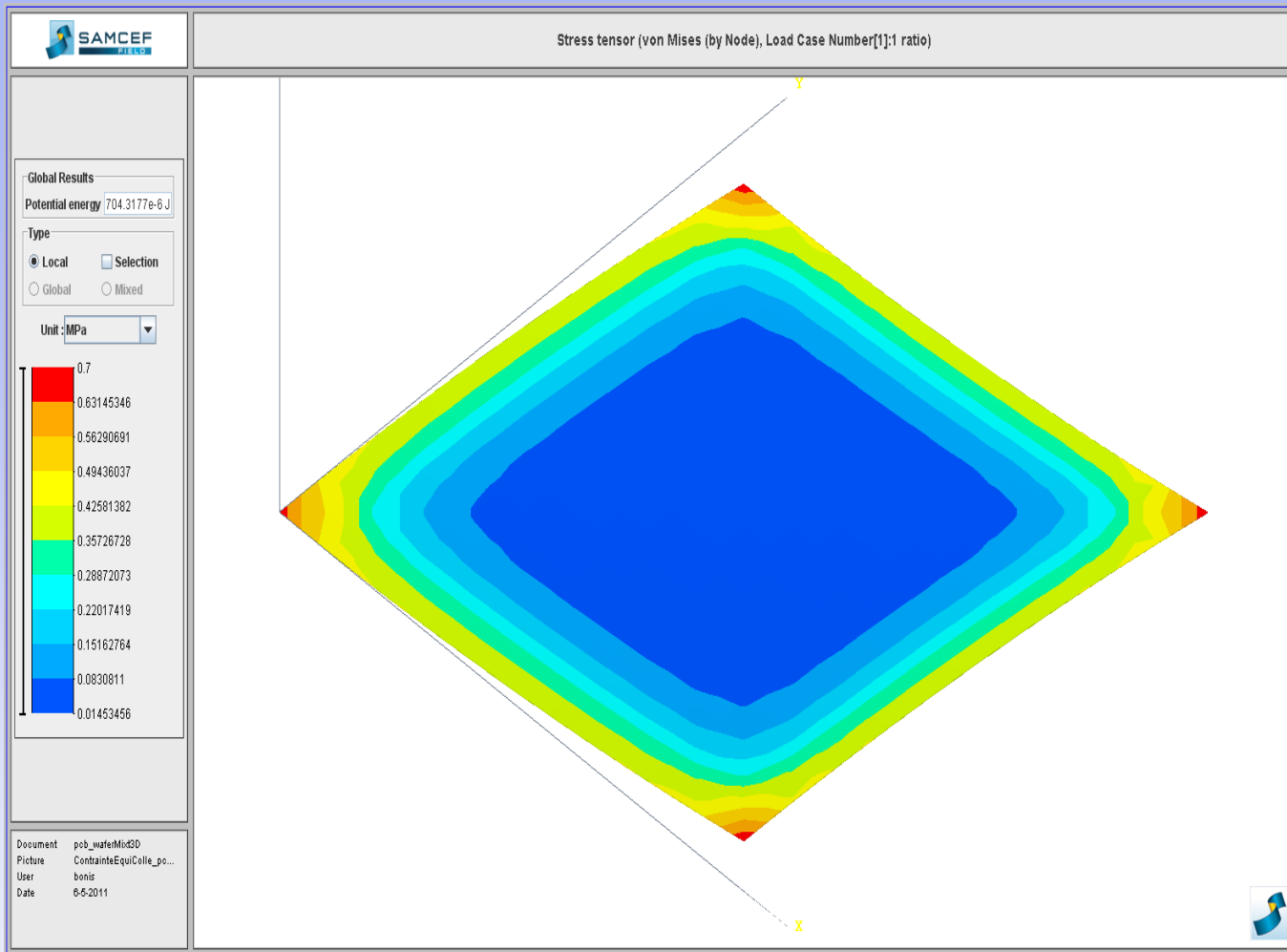


ASU Deformations (in direction z) of  $\frac{1}{4}$  PCB-wafer  
Max deflection was 0.21mm



Von Mises Equivalent Stress in wafer  
 Max stress = 6.1mm





Von Mises Equivalent Stress in Glue  
Max stress = 0.7MPa

## With PCB initial deflection = 1mm

### Stress in Wafer:

- Calculated Maximum stress is 6.1 MPa.
- Failure flexion stress of wafer is 140 MPa. => OK

### Stress in Glue:

- Calculated Maximum stress 0.7 MPa.
- But in case of **points of glue**, totale glue surface was only 20% of wafer surface. And, glue drop shape introduce a stress intensity factor ( $K = 2$  or  $3$  minimum). So, the **Effective stress in glue** become near **7 or 10 MPa**. Failure stress of glue is 8.7 MPa. => OK !  
With security coefficient of 2, **initial PCB deflection must be less than 0.5 mm**

- If **ACF** can be used for PCB-wafer connexion. Failure stress of ACF is 10 to 50 MPa. => OK

## Ways to minimize PCB deflection

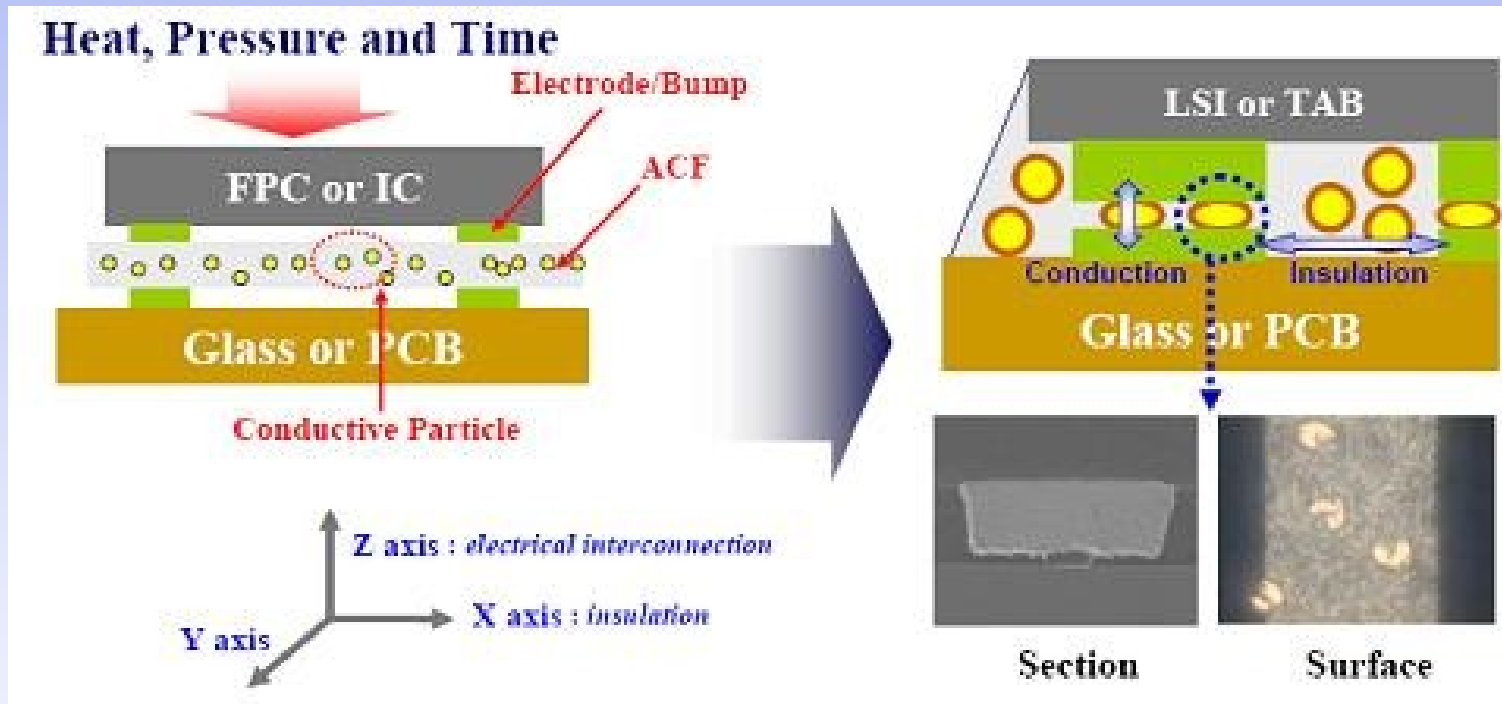
- Balance :
  - Each core must be as symmetric as possible
  - Cores must be as similar as possible.
  - Cores with equivalent mechanical characteristics.
    - FEV7 composition :
      - Cover part of PCB, on the top:  
300 micron of preg with 40 micron of copper  
=> 13.33% of copper
      - Main pcb  
525 micron of preg with 231 micron of copper.  
=>44% of copper.
    - It's perhaps better to introduce more copper in cover part of PCB
  
- Decrease process temperature when possible

=>Think about mechanical constraints during electronics design

**Challenge : Less than 0.5mm deflection if possible.**



# ACF principle



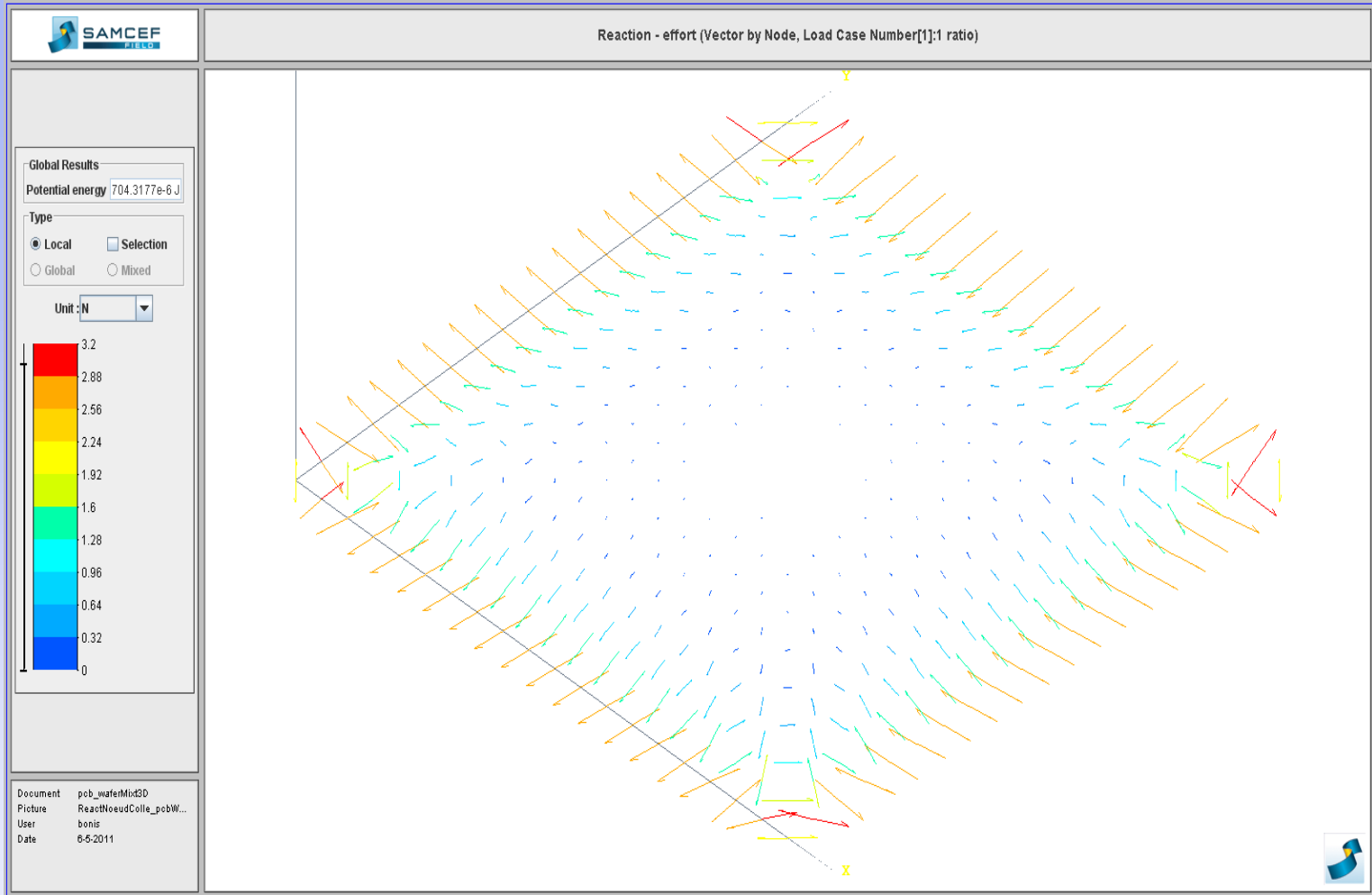


## Common ACF parameters

Assembly Type	Adhesive Type	Time(Sec)	Temp (° C)	Pressure
Flex-on-Glass (FOG)	Epoxy	10-12	170-200	2-4MPa▲
Chip-on-Glass(COG)	Epoxy	5-7	190-220	50-150MPa※
Chip-on-Flex (COF)	Epoxy	5-10	190-220	30-150MPa※
Flex-on-Board (FOB)	Epoxy	10-12	170-190	1-4MPa▲
Flex-on-Board (FOB)	Acryl	5-10	130-170	1-4MPa▲
Flex-on-Flex (FOF)	Epoxy	10-12	170-190	1-4MPa▲
Flex-on-Flex (FOF)	Acryl	5-10	130-170	1-4MPa▲

## Towards Chip encapsulation

- Bonding Wire were at 0.2mm from PCB surface.
- Resin Aradilte 20/20 used (the most flowing)
- Hopeful first test (flat surface achieved)
- Next test under vacuum to avoid bubbles



Node reaction in glue points (equivalent pads positions)